Application Number: 09/696,232 Attorney Docket Number: 07553.0017

Page 4, please amend the paragraph beginning with "In addition" to read as follows:

In addition, if the flow rate ratio of C_4F_8 and N_2 (N_2 flow rate / C_4F_8 flow rate) in the processing gas is less than 10, an etching stop occurs and, as a result, deep etching is not achieved. Accordingly, it is desirable to set the flow rate ratio of C_4F_8 and N_2 in the processing gas essentially within a range of $10 \le (N_2$ flow rate / C_4F_8 flow rate).

IN THE CLAIMS:

Please cancel claims 6 and 12 without prejudice or disclaimer of the subject matter thereof; amend claims 1 and 7; and add new claims 13-16, as follows:

1. (Amended) An etching method for etching an etching target film formed on a substrate placed inside an airtight processing chamber by inducing a processing gas into said processing chamber, wherein;

said processing gas contains at least a $C_x F_y$ gas and N_2 , but does not contain O_2 ; and

said etching target film is constituted of an upper organic film containing Si and a lower SiO₂ film.

FINNEGAN HENDERSON FARABOW GARRETT & DUNNER!!!

1300 I Street, NW Washington, DC 20005 202.408.4000 Fax 202.408.4400 www.finnegan.com (Amended) An etching method for etching an etching target film formed on a substrate placed inside an airtight processing chamber by inducing a processing gas into said processing chamber, wherein;

Application Number: 09/696,232 Attorney Docket Number: 07553.0017

said processing gas contains at least a C_xF_y gas and N₂, but does not contain O₂; and

said etching target film is constituted of an upper organic film containing Si and a lower SiN film.

-- 13. (New) An etching method according to claim 1, wherein; said C_xF_y gas is CF₄.

AID

- 14. (New) An etching method according to claim 13, wherein; the flow rate ratio of CF₄ and N₂ in said processing gas is essentially set within a range of $1 \le (N_2 \text{ flow rate } / CF_4 \text{ flow rate}) \le 4$.
- 15. (New) An etching method according to claim 7, wherein; said C_xF_y gas is C_4F_8 .
- 16. (New) An etching method according to claim 15, wherein; the flow rate ratio of C₄F₈ and N₂ in said processing gas is essentially set within a range of $10 \le (N_2 \text{ flow rate } / C_4F_8 \text{ flow rate})$. --

FINNEGAN HENDERSON FARABOW GARRETT & DUNNER世

1300 I Street, NW Washington, DC 20005 202.408.4000 Fax 202.408.4400 www.finnegan.com

IN THE DRAWINGS:

Submitted herewith is a Request for Approval of Drawing Change. Subject to the approval of the Examiner, Applicants propose to replace "N2," "H2," and "CF4" in Fig. 1